



Call For Papers **ATS'12**

The 21st Asian Test Symposium

November 19-22, 2012, Toki Messe Niigata Convention Center, Niigata, Japan

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SCOPE

The Asian Test Symposium (ATS) provides an international forum for engineers and researchers from all countries of the world, especially from Asia, to present and discuss various aspects of device, board and system testing with design, manufacturing and field considerations in mind.

Major topics include, but are not limited to:

- Automatic Test Pattern Generation (ATPG)
- Analog Test / Mixed-Signal Test
- Boundary Scan Test
- Board and System Test
- Built-In Self-Test
- Design for Testability (DFT)
- Design Verification and Validation
- Defect-Based Testing
- Delay and Performance Test
- Diagnosis and Debug
- Dependable System
- Economics of Test
- Fault Modeling and Simulation
- Fault Tolerance
- High-Speed I/O Test / RF Testing
- Memory Test / FPGA Test
- On-Line Test
- System-on-a-Chip Test
- System-in-package (SiP)/ 3D Test
- Software Testing / Software Design for Testing
- Test Compression
- Temperature/Power-aware Test
- Test Quality
- Yield Analysis and Enhancement

SUBMISSIONS

Regular Session: The ATS'12 Program Committee invites original, unpublished paper submissions for ATS'12. Paper submissions should be complete manuscripts, up to six pages (including figures, tables, and bibliography) in a standard IEEE two-column format; papers exceeding the page limit will be returned without review. Authors should clearly explain the significance of the work, highlight novel features, and describe its current status. On the title page, please include: author name(s) and affiliation(s), and the mailing address, phone number, fax number, and e-mail address of the contact author. An abstract of 50 words or less and 5-10 keywords are also required. All submissions are to be made electronically through the ATS'12 website. Detailed instructions for submissions are to be found at the ATS'12 website. Electronic submissions in PDF files are strongly recommended. A submission will be considered as evidence that, upon acceptance, the author(s) will submit a final camera-ready version of the paper for inclusion in the proceedings, and will present the paper at the symposium. The registration of at least one author is required for publication.

Industry Session: This session will address a wide range of practical problems in LSI test, board and system test, diagnosis, failure analysis, design verification, and so on. The session will consist of poster presentations and optional oral presentations. A one-page abstract is required for submission. Each submission should also include the complete address and designate a contact person and a presenter. Abstract submissions should be emailed to Industry Chair (ats12-industry@aries30.cse.kyutech.ac.jp).

KEY DATES (Regular Session)

Paper submission deadline: May 25, 2012

Notification of acceptance: Aug. 5, 2012

Camera ready manuscript: Aug. 31, 2012

KEY DATES (Industry Session)

Paper submission deadline: Jul. 5, 2012

Notification of acceptance: Aug. 5, 2012

Camera ready manuscript: Aug. 31, 2012



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ATS2012 WEBSITE <http://aries3a.cse.kyutech.ac.jp/~ats12/>

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